

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10558994	FURUKAWA ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	ANAND BHATNAGAR	2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	Previous search by examiner Max Shikhman	09/19/09	/AB/
382	100,302,303	09/19/09	/AB/
345	647,643,644,645,674	09/19/09	/AB/
348	230.1,228.1,231.6,231.99,231.1,231.3	09/19/09	/AB/
700	2,4	09/19/09	/AB/
updated	see sheet	09/19/09	/AB/

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East	09/19/09	/AB/
Inventor	09/19/09	/AB/
IEEE	09/19/09	/AB/

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
Interference	see sheet	09/19/09	/AB/

09/19/09

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Primary Examiner.Art Unit 2624